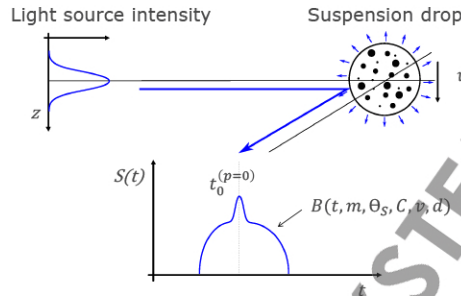
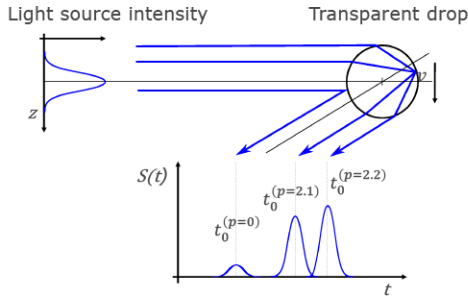


Spray characteristics play an important role in a wide range of industrial applications, such as spray coating, spray drying and crop protection. Spray characterization methods are therefore essential tools for quality assurance, development and optimization of these processes.

## Light scattering of a spherical drop passing through a focused laser beam



Legend:

- $S(t)$  Time-shift signal
- $B(t)$  Baseline signal
- $m$  Relative refractive index
- $\theta_S$  Scattering angle
- $\theta_i$  Incident angle
- $A$  Amplitude
- $p$  Scattering order
- $w$  Laser beam width
- $v$  Drop velocity
- $d$  Drop size
- $t$  Time
- $t_0$  Peak position
- $C$  Concentration
- $z$  Propagation direction

Scattering light from transparent particles can be interpreted as the superposition of all scattering orders present at the detector location:

$$S(t) = \sum_{\substack{p=0 \\ p=2.1 \\ p=2.2}} A_p(m, \theta_S) \exp\left(-\frac{2(t - t_0^{(p)})^2}{(w/v)^2}\right)$$

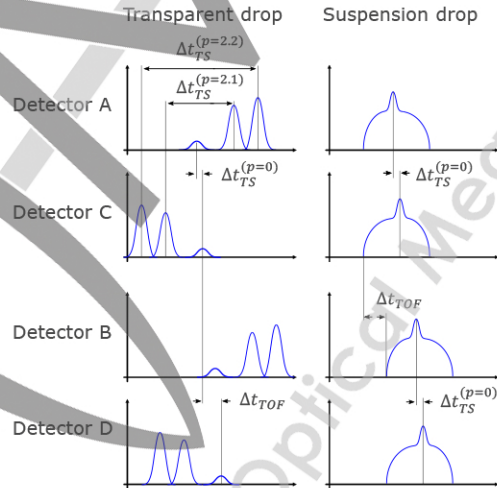
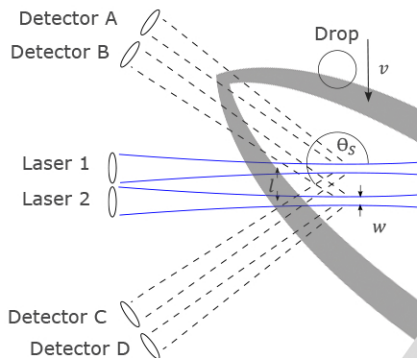
For suspensions, refracted light rays do not propagate undisturbed through the drop. The signal arising from this portion of scattered light is termed the baseline signal  $B(t)$ . The reflective signal remains unaltered:

$$S(t) = A_{(p=0)}(m, \theta_S) \exp\left(-\frac{2(t - t_0^{(p=0)})^2}{(w/v)^2}\right) + B(t, m, \theta_S, C, v, d)$$

## Principles of the Time-Shift technique

Schematic sensor setup, where the Time-of-Flight (TOF) and Time-Shift (TS) technique are combined:

The scattered light is focused onto photo detectors. Each photo detector provides a time-shift signal:



Drop size and velocity are correlated with the time between individual scattering orders:

$$\Delta t_{TS}^{(p)} = \frac{d}{v} f(\theta_i^{(p)}, \theta_S, m)$$

$$\Delta t_{TOF} = \frac{l}{v}$$

Where the function  $f$  indicates the relative distance between incident points. The incident angle  $\theta_i$  is solved from:

$$\sin(\theta_i^{(p)}) = m \sin\left(\frac{\pi}{2p} - \frac{\theta_S}{2p} + \frac{\theta_i^{(p)}}{p}\right)$$

for  $p \in [2, 4, 6, \dots]$

$$\sin(\theta_i^{(p=0)}) = \cos\left(\frac{\theta_S}{2}\right)$$

**TOF:** Time difference between the signal at detector **A** and detector **B**. The same holds for detector **C** and detector **D**.

**TS:** Time difference between the signal at detector **A** and detector **C**. The same holds for detector **B** and detector **D**.

## Measurement results

